

**Notice of Allowability**

Application No.

10/797,798

Examiner

Sang Nguyen

Applicant(s)

MYDLACK ET AL.

Art Unit

2877

**-- The MAILING DATE of this communication appears on the cover sheet with the correspondence address--**

All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. **THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS.** This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.

1. ☒ This communication is responsive to 08/15/06.
2. ☒ The allowed claim(s) is/are 1-19, 22-25, and 27-33 which has been renumbered as indicated claims 1-30.
3. ☐ Acknowledgment is made of a claim for foreign priority under 35 U.S.C. § 119(a)-(d) or (f).
- a) ☐ All b) ☐ Some\* c) ☐ None of the:
1. ☐ Certified copies of the priority documents have been received.
2. ☐ Certified copies of the priority documents have been received in Application No. \_\_\_\_\_.
3. ☐ Copies of the certified copies of the priority documents have been received in this national stage application from the International Bureau (PCT Rule 17.2(a)).

\* Certified copies not received: \_\_\_\_\_.

Applicant has THREE MONTHS FROM THE "MAILING DATE" of this communication to file a reply complying with the requirements noted below. Failure to timely comply will result in ABANDONMENT of this application.  
**THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.**

4. ☐ A SUBSTITUTE OATH OR DECLARATION must be submitted. Note the attached EXAMINER'S AMENDMENT or NOTICE OF INFORMAL PATENT APPLICATION (PTO-152) which gives reason(s) why the oath or declaration is deficient.
5. ☐ CORRECTED DRAWINGS (as "replacement sheets") must be submitted.
- (a) ☐ including changes required by the Notice of Draftsperson's Patent Drawing Review (PTO-948) attached
- 1) ☐ hereto or 2) ☐ to Paper No./Mail Date \_\_\_\_\_.
- (b) ☐ including changes required by the attached Examiner's Amendment / Comment or in the Office action of Paper No./Mail Date \_\_\_\_\_.
- Identifying indicia such as the application number (see 37 CFR 1.84(c)) should be written on the drawings in the front (not the back) of each sheet. Replacement sheet(s) should be labeled as such in the header according to 37 CFR 1.121(d).
6. ☐ DEPOSIT OF and/or INFORMATION about the deposit of BIOLOGICAL MATERIAL must be submitted. Note the attached Examiner's comment regarding REQUIREMENT FOR THE DEPOSIT OF BIOLOGICAL MATERIAL.

**Attachment(s)**

1. ☐ Notice of References Cited (PTO-892)
2. ☐ Notice of Draftsperson's Patent Drawing Review (PTO-948)
3. ☐ Information Disclosure Statements (PTO/SB/08),  
Paper No./Mail Date \_\_\_\_\_
4. ☐ Examiner's Comment Regarding Requirement for Deposit  
of Biological Material
5. ☐ Notice of Informal Patent Application
6. ☒ Interview Summary (PTO-413),  
Paper No./Mail Date 9/25/06.
7. ☒ Examiner's Amendment/Comment
8. ☒ Examiner's Statement of Reasons for Allowance
9. ☐ Other \_\_\_\_\_.

### EXAMINER'S AMENDMENT

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

Authorization for this examiner's amendment was given in a telephone interview with Mr. Troy R. Lester (Reg. No. 36,200) on September 25, 2006.

**The application has been amended as follows by the amendment on 08/15/06 with claims 1, 25, and 29:**

1. (Twice Amended) A method of inspecting a curved object, comprising:  
acquiring an inspection image of a curved object using a detector;  
adjusting the inspection image to minimize curvature distortion in an adjusted image; and  
comparing the adjusted image with a predetermined master image;  
further comprising the step of adjusting the brightness values of the image to account for non-uniform illumination, wherein the step of adjusting the brightness comprises the steps of acquiring a scanned image of a uniformly shaded object; measuring brightness values for each pixel in said scanned image; calculating a reference brightness value; establishing scale factors for each pixel in said scanned image based on the reference brightness value; and adjusting corresponding pixel brightness values in the inspection image by applying the scale factors for correcting of curvature distortion.

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25. (Twice Amended) A method for inspecting a curved object comprising the steps of

- acquiring an image of a white calibration object as a predetermined master image;
- acquiring an inspection image of a curved object using a detector; and
- adjusting the inspection image to adjust the brightness to account for non-uniform illumination comprising the steps of measuring brightness values for each pixel in the master image; calculating a reference brightness value; establishing scale factors for each pixel in the master image based on the reference brightness value; and adjusting corresponding pixel brightness values in the inspection image by applying the scale factors for correcting of curvature distortion.

29. (Twice Amended) A method of inspecting a curved object, comprising:

- acquiring an inspection image of a curved object using a detector;
- adjusting the inspection image to minimize curvature distortion in a adjusted image; and
- comparing the adjusted image with a predetermined master image for correcting of curvature distortion;

wherein the step of adjusting the inspection image to minimize curvature distortion comprises the steps of:

- adjusting at least one pixel in the inspection image in one direction using the formula:

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$$X_{adj} = R \cdot \arcsine (X_i / R); \text{ and}$$

adjusting said pixel in the other direction using the formula:  $Y_{adj} = C - ((C - Y_i) / \cos \theta)$

where R is the radius of the curved object, (X<sub>i</sub>, Y<sub>i</sub>) are the coordinates of said pixel, C is a reference point on the inspection image,  $\theta$  is the angular location above or below the equator of the curved object, and (X<sub>adj</sub>, Y<sub>adj</sub>) are the coordinates of the adjusted pixel.

The following is an examiner's statement of reasons for allowance:

Independent claims 1, 25, and 29 are allowed over the prior art of the record for the reasons set forth in the previous Office action on 03/15/06 with pages 12-13.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

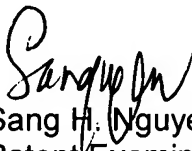
Any inquiry concerning this communication or earlier communications from the examiner should be directed to Sang Nguyen whose telephone number is (571) 272-2425. The examiner can normally be reached on 9:30 am to 7:00 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Gregory J. Toatley, Jr. can be reached on (571) 272-2800 ext. 77. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

September 25, 2006

  
Sang H. Nguyen  
Patent Examiner  
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